Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,983	KOIKE, HIDEHARU
Examiner	Art Unit
 Hai L. Nguyen	2816

	SEAR	CHED	
Class	Subclass	Date	Examiner
327 j	551,552, 309-311, 313,318	2/1/2005	HLN.
	319,321		
	327,328		
V	379,180		
361	91.1,225		
257	355-357	V	V

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u></u>				

	CH NOTES ARCH STRATEGY	()
	DATE	EXMR
Shepardize Search	2/1/2005	HLN